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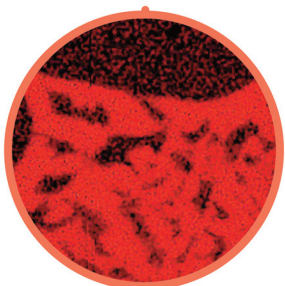
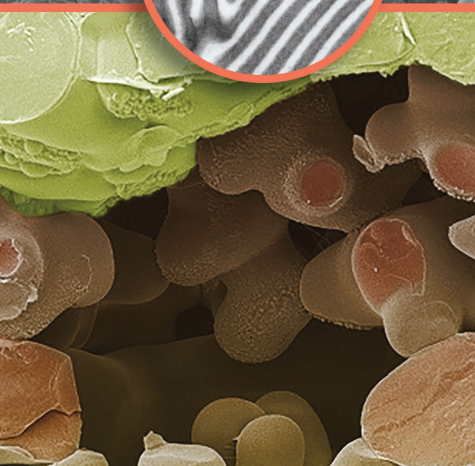
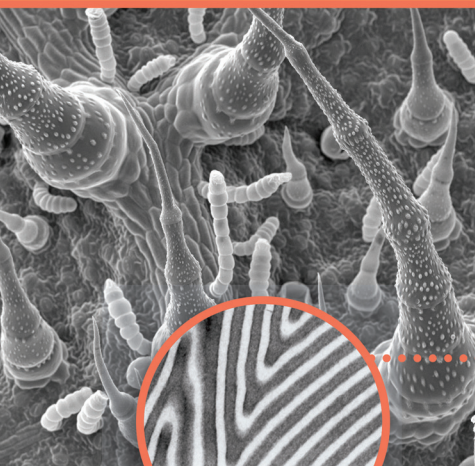
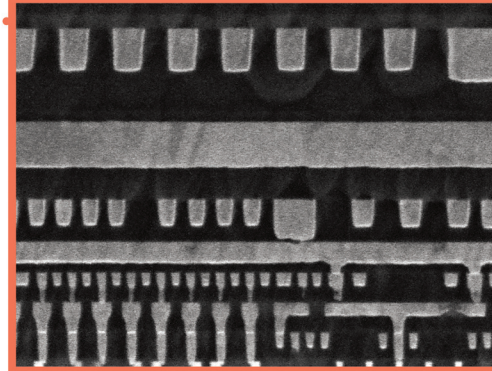
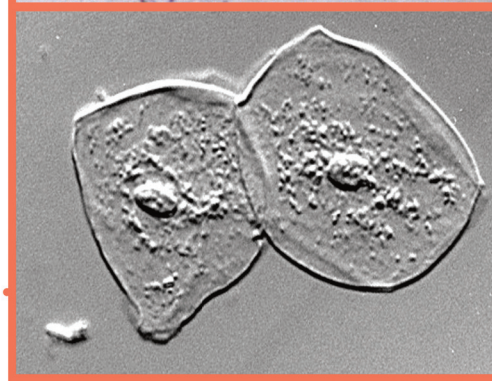
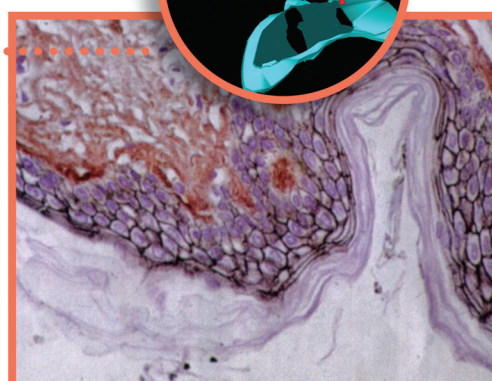
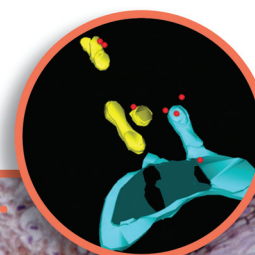
Introduction to Microscopy Techniques

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The *All-New* Hitachi ETHOS SEM-FIB combines ultra-high resolution imaging and elemental analysis at low voltages with ion optics for nm-scale precision processing.



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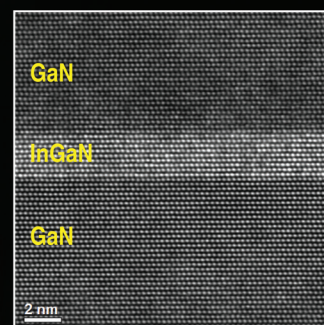
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200 kv ADF STEM Image of processed lamella by Triple Beam Ar Ion at 1kV

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